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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.	
09/681,643	05/15/2001	Takatoshi Tsujimura	JP920000112US1	8744	
877	7590 09/04/2002				
IBM CORPORATION, T.J. WATSON RESEARCH CENTER			EXAMINER		
P.O. BOX 218 YORKTOWN HEIGHTS, NY 10598			COLEMAN, WILLIAM D		
			ART UNIT	PAPER NUMBER	
			2823		

DATE MAILED: 09/04/2002

Please find below and/or attached an Office communication concerning this application or proceeding.

		Арр	lication No.	Applicant(s)	
	Office Action Summary		81,643	TSUJIMURA ET	AL.
			niner	Art Unit	
<b>,</b>	· 		avid Coleman	2823	
Period fo	The MAILING DATE of this commu	inication appears o	on the cover sheet v	vith the correspondence a	address
I HE N - Exter after - If the - If NO - Failur - Any re	ORTENED STATUTORY PERIOD MAILING DATE OF THIS COMMUN asions of time may be available under the provision SIX (6) MONTHS from the mailing date of this comperiod for reply specified above is less than thirty period for reply is specified above, the maximum see to reply within the set or extended period for reply received by the Office later than three months dipatent term adjustment. See 37 CFR 1.704(b).	NICATION.  ns of 37 CFR 1,136(a). In  nmunication.  (30) days, a reply within the  statutory period will apply  bly will, by statute, cause the	no event, however, may a ne statutory minimum of thi and will expire SIX (6) MO	reply be timely filed  rty (30) days will be considered tim  NTHS from the mailing date of this  RANDONED (35 U.S.C. 5 133)	ely. communication
1)[	Responsive to communication(s) t	filed on 02 July 20	02		
2a) <u> </u>	This action is <b>FINAL</b> .		on is non-final.		
3)				44	
,	Since this application is in condition closed in accordance with the praction of Claims	ctice under <i>Ex par</i>	te Quayle, 1935 C.	D. 11, 453 O.G. 213.	he merits is
4)	Claim(s) <u>1-16</u> is/are pending in the	application.			
	a) Of the above claim(s) <u>11-16</u> is/a	• •	consideration.		
	Claim(s) is/are allowed.				
	Claim(s) <u>1-10</u> is/are rejected.				
	Claim(s) is/are objected to.				
	Claim(s) are subject to restri	ction and/or electi	on requirement.		
	on Papers		4		
9)[] T	he specification is objected to by th	ne Examiner.			
10)[ T	he drawing(s) filed on is/are	: a) ☐ accepted or t	o) objected to by t	he Examiner.	
	Applicant may not request that any ob	jection to the drawir	ng(s) be held in abey	ance. See 37 CFR 1.85(a).	
11) 🗌 T	he proposed drawing correction file	ed on is: a)[	☐ approved b)☐ c	isapproved by the Examir	ner.
	If approved, corrected drawings are re	equired in reply to thi	s Office action.		
12) 🗌 T	he oath or declaration is objected to	o by the Examiner			
riority ur	nder 35 U.S.C. §§ 119 and 120				
13) 🗌 🛚 A	Acknowledgment is made of a claim	n for foreign priorit	y under 35 U.S.C.	§ 119(a)-(d) or (f).	
a)[	All b) Some * c) None of:				
1	I. Certified copies of the priority	documents have	been received.		
2	2. Certified copies of the priority	documents have	been received in A	pplication No	
	B. Copies of the certified copies application from the Interret the attached detailed Office action	of the priority doc national Bureau (P	uments have been CT Rule 17.2(a)).	received in this National	Stage
14) 🗌 Ac	knowledgment is made of a claim f	or domestic priorit	y under 35 U.S.C.	§ 119(e) (to a provisiona	I application).
a)	☐ The translation of the foreign lar knowledgment is made of a claim t	nguage provisiona	l application has be	een received.	•
ttachment(s					
) Notice	of References Cited (PTO-892) of Draftsperson's Patent Drawing Review (P ation Disclosure Statement(s) (PTO-1449) P		F-1	Summary (PTO-413) Paper No nformal Patent Application (PT	
Patent and Trad O-326 (Rev.		Office Action Sun	nmary	Part	of Paper No. 7

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### **DETAILED ACTION**

#### Election/Restrictions

1. Claims 11-16 withdrawn from further consideration pursuant to 37 CFR 1.142(b), as being drawn to a nonelected group II invention, there being no allowable generic or linking claim. Applicant timely traversed the restriction (election) requirement in Paper No. 6.

## Response to Arguments

2. Applicant's arguments with respect to claims 1-10 have been considered but are moot in view of the new ground(s) of rejection.

## Claim Rejections - 35 USC § 103

- 3. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
  - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 4. Claims 1-10 are rejected under 35 U.S.C. 103(a) as being unpatentable over Ohnuma et al., U.S. Patent 6,072,193 in view of Gardner et al., U.S. Patent 6,066,519.
- 5. Pertaining to claims 1 and 2, <u>Ohnuma</u> discloses a semiconductor process substantially as claimed. See **FIGS. 1A-2D**, where <u>Ohnuma</u> teaches a manufacturing method of an active matrix device (column 17, line 62) including a top gate type TFT, which comprises a process of forming the top gate type TFT, wherein the process of forming the top gate type TFT includes the steps of:

arranging a substrate 101 having source 125 and drain electrodes 126 formed therein in

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the processing chamber; doping the source and drain electrodes with P (phosphorous), (column 3, lines 51-54); and forming an a-Si layer 103 and a gate insulating film 104 in the processing chamber. However, Ohnuma fails to disclose forming an oxide film on an inner wall of a CVD processing chamber. Gardner teaches forming an oxide on an inner wall of a CVD processing chamber (column 6, lines 8-14). In view of Gardner, it would have been obvious to one of ordinary skill in the art because when forming a gate dielectric residual oxide forms on the chamber walls (column 6, lines 10-12).

- 6. Pertaining to claim 2, Ohnuma fails to disclose removing the oxide film form the inner wall after the step of forming the a-Si layer and the gate insulating layer. Gardner teaches the step of removing oxide between runs. In view Gardner, it would have been obvious to one of ordinary skill in the are to remove oxide from the chamber walls after the step of forming the a-Si layer and the gate insulating film because the a silicon gate dielectric layer may be formed in a highly controlled manner (column 6, lines 21-23).
- 7. Pertaining to claim 3, Ohnuma teaches a manufacturing method of an active matrix device according to claim 1,

wherein the oxide film contains SiOx.

- 8. Pertaining to claim 4, Ohnuma teaches a manufacturing method of an active matrix device according to claim 1, wherein the active matrix device is a liquid crystal display (column 17, line 62).
- 9. Pertaining to claim 5, Ohnuma teaches a manufacturing method of an active matrix device according to claim 1, wherein the active matrix device is an electroluminescence display (column 17, line 62).

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- 10. Pertaining to claim 6, Ohnuma teaches a manufacturing method of an active matrix device according to claim 2, wherein the oxide film contains SiOx.
- Pertaining to claim 7, Ohnuma teaches a manufacturing method of an active matrix device according to claim 2, wherein the active matrix device is a liquid crystal display.
- 12. Pertaining to claim 8, Ohnuma teaches a manufacturing method of an active matrix device according to claim 3, wherein the active matrix device is a liquid crystal display.
- 13. Pertaining to claim 9, Ohnuma teaches a manufacturing method of an active matrix device according to claim 2, wherein the active matrix device is an electroluminescence display.
- 14. Pertaining to claim 10, Ohnuma teaches a manufacturing method of an active matrix device according to claim 3, wherein the active matrix device is an electroluminescence display.

### Conclusion

15. Any inquiry concerning this communication or earlier communications from the examiner should be directed to W. David Coleman whose telephone number is 703-305-0004. The examiner can normally be reached on 9:00 AM-5:00 PM.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor, Wael M. Fahmy can be reached on 703-308-4918. The fax phone numbers for the organization where this application or proceeding is assigned are 703-308-7722 for regular communications and 703-308-7721 for After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be directed to the receptionist whose telephone number is 703-308-0956.

W. David Coleman Examiner Art Unit 2823

WDC August 30, 2002

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